

Features

- Uses CRM(CQ) advanced Trench MOS technology
- Extremely low on-resistance $R_{DS(on)}$
- Excellent $Q_g \times R_{DS(on)}$ product(FOM)
- Qualified according to JEDEC criteria

Product Summary

V_{DS}	40V
$R_{DS(on)}$ typ.	4.5mΩ
I_D	80A

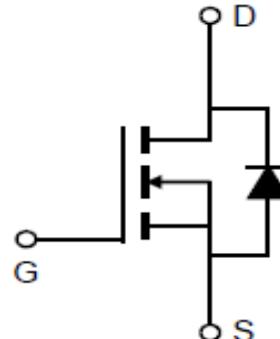
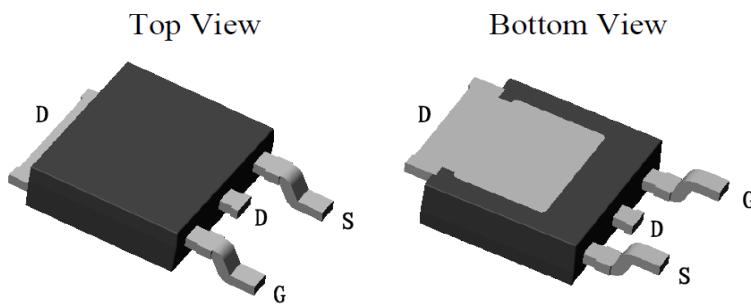
Applications

- Motor control and drive
- Battery management
- UPS (Uninterruptible Power Supplies)

100% DVDS Tested

100% Avalanche Tested

TO-252



Package Marking and Ordering Information

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRTD063N04L	CRTD063N04L	TO-252	Reel	N/A	N/A	2500pcs

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V_{DS}	40	V
Continuous drain current $T_C = 25^\circ\text{C}$ (Silicon limit) $T_C = 25^\circ\text{C}$ (Package limit) $T_C = 100^\circ\text{C}$ (Silicon limit)	I_D	88 80 56	A
Pulsed drain current ($T_C = 25^\circ\text{C}$, t_p limited by $T_{j,\max}$)	$I_{D\text{ pulse}}$	320	A
Avalanche energy, single pulse ($L=0.5\text{mH}$, $R_g=25\Omega$)	E_{AS}	81	mJ
Gate-Source voltage	V_{GS}	± 20	V
Power dissipation ($T_C = 25^\circ\text{C}$)	P_{tot}	92	W
Operating junction and storage temperature	T_j , T_{stg}	-55...+150	°C

Thermal Resistance

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R _{thJC}	1.37	°C/W
Thermal resistance, junction – ambient(min. footprint)	R _{thJA}	94	

Electrical Characteristic (at T_j = 25 °C, unless otherwise specified)

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

Static Characteristic

Drain-source breakdown voltage	BV _{DSS}	40	-	-	V	V _{GS} =0V, I _D =250uA
Gate threshold voltage	V _{GS(th)}	1.2	1.7	2.3	V	V _{DS} =V _{GS} , I _D =250uA
Zero gate voltage drain current	I _{DSS}	-	0.1	1	μA	V _{DS} =40V, V _{GS} =0V T _j =25°C T _j =125°C
Gate-source leakage current	I _{GSS}	-	1	100	nA	V _{GS} =20V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	4.5	6.3	mΩ	V _{GS} =10V, I _D =40A, T _j =25°C
		-	8.3	10		T _j =150°C
		-	5.5	7.5		V _{GS} =4.5V, I _D =30A,
Transconductance	g _f	-	120	-	S	V _{DS} =5V, I _D =40A

Dynamic Characteristic

Input Capacitance	C _{iss}	-	2246	-	pF	V _{GS} =0V, V _{DS} =20V, f=1MHz
Output Capacitance	C _{oss}	-	319	-		
Reverse Transfer Capacitance	C _{rss}	-	155	-		
Gate Total Charge	Q _G	-	47	-	nC	V _{GS} =10V, V _{DS} =20V, I _D =40A, f=1MHz
Gate-Source charge	Q _{gs}	-	8.9	-		
Gate-Drain charge	Q _{gd}	-	9.9	-		
Turn-on delay time	t _{d(on)}	-	9	-	ns	V _{GS} =10V, V _{DD} =20V, R _{G_ext} =3Ω, ID=40A,
Rise time	t _r	-	31	-		
Turn-off delay time	t _{d(off)}	-	54	-		
Fall time	t _f	-	18	-	Ω	V _{GS} =0V, V _{DS} =0V, f=1MHz
Gate resistance	R _G	-	1.5	-		

Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	V_{SD}	-	0.9	1.3	V	$V_{GS}=0V, I_{SD}=40A$
Body Diode Reverse Recovery Time	t_{rr}	-	19	-	ns	$I_F=40A, dI/dt=100A/\mu s$
Body Diode Reverse Recovery Charge	Q_{rr}	-	10	-	nC	

Typical Performance Characteristics

Fig 1: Output Characteristics

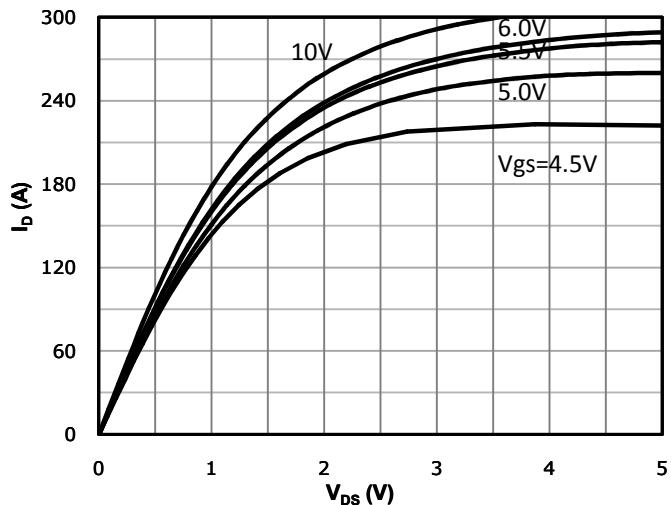


Fig 2: Transfer Characteristics

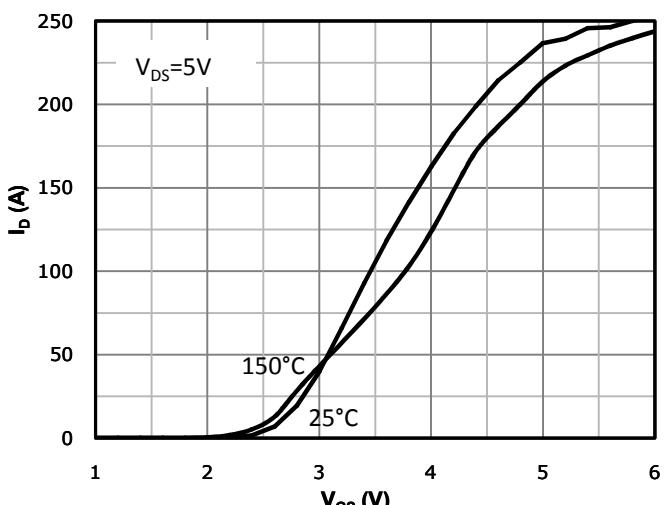


Fig 3: Rds(on) vs Drain Current and Gate Voltage

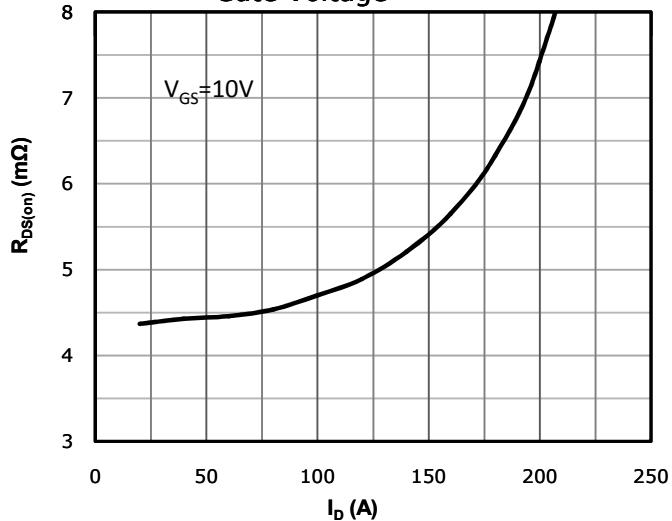


Fig 4: Rds(on) vs Gate Voltage

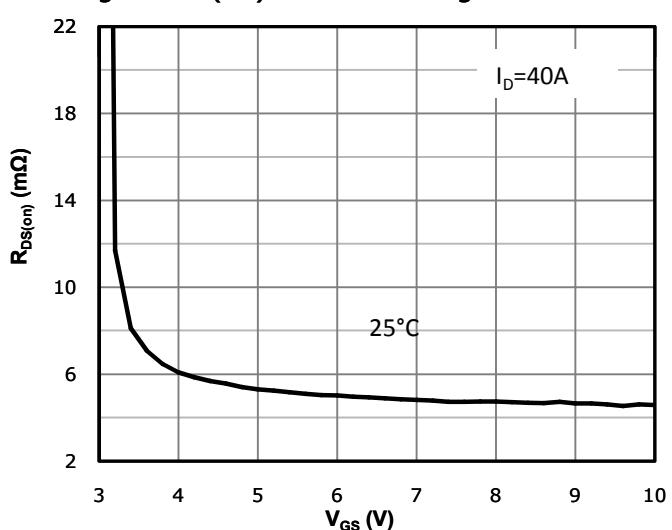


Fig 5: Rds(on) vs. Temperature

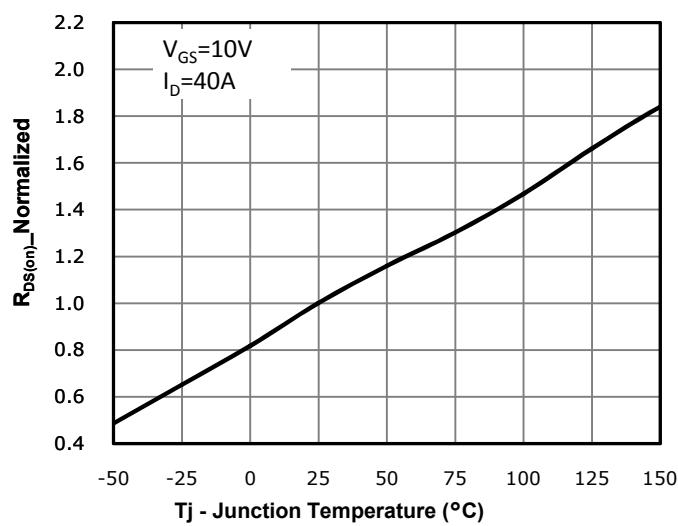


Fig 6: Capacitance Characteristics

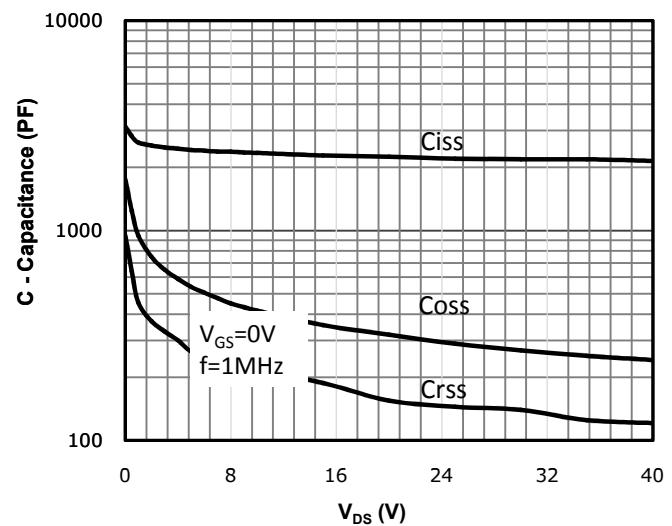


Fig 7: Gate Charge Characteristics

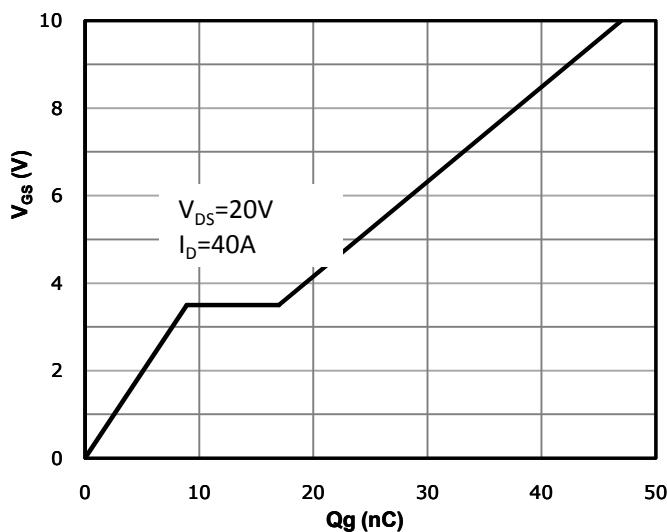


Fig 8: Body-diode Forward Characteristics

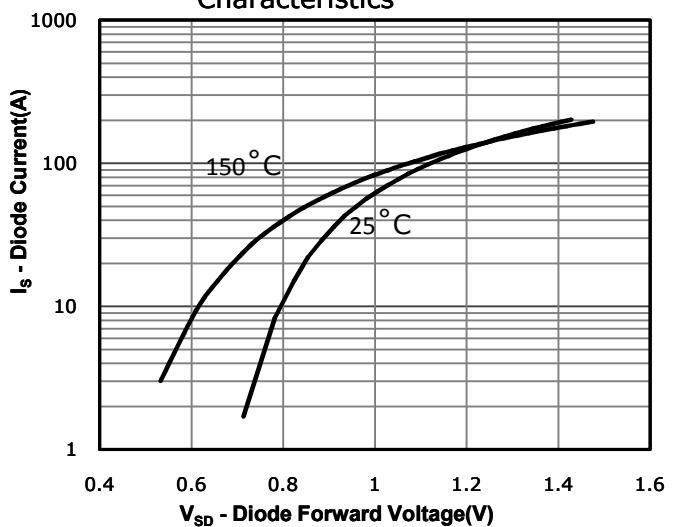


Fig 9: Power Dissipation

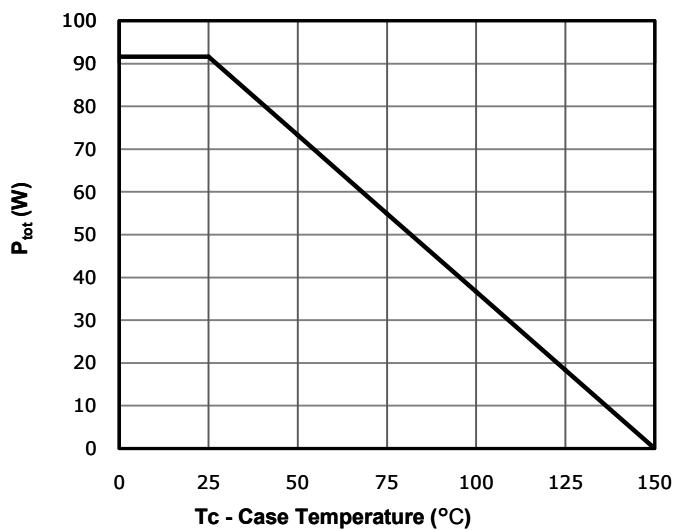


Fig 10: Drain Current Derating

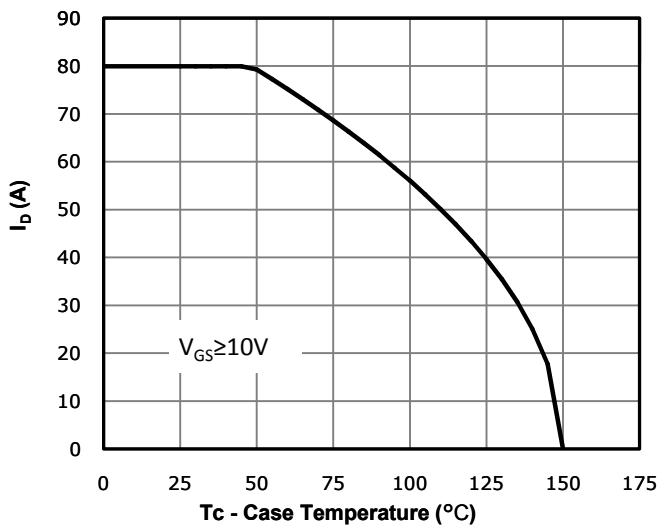


Fig 11: Safe Operating Area

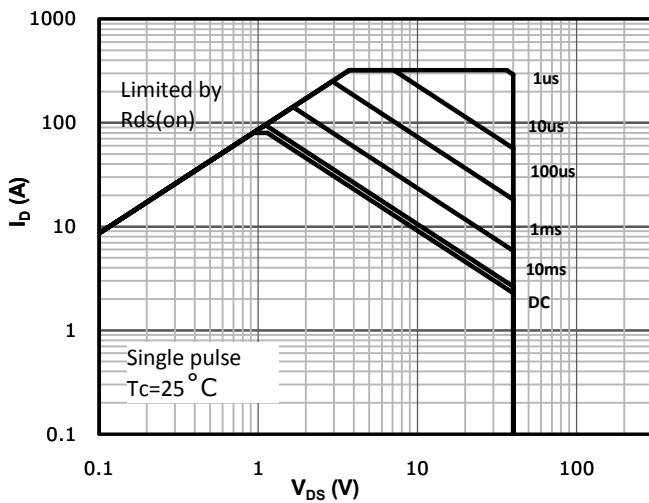
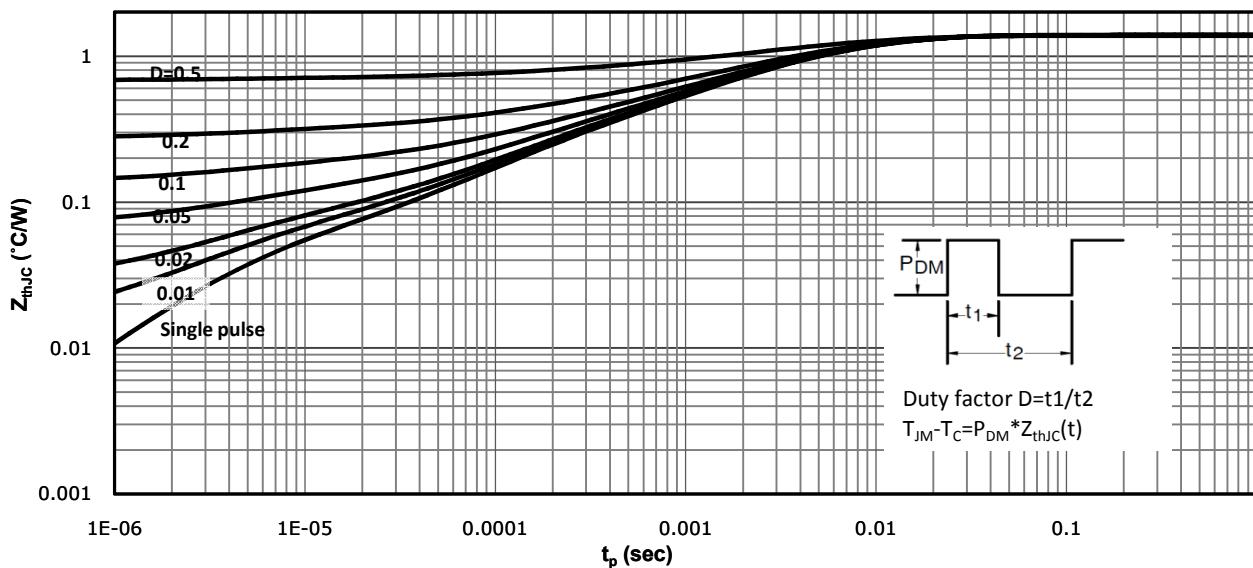
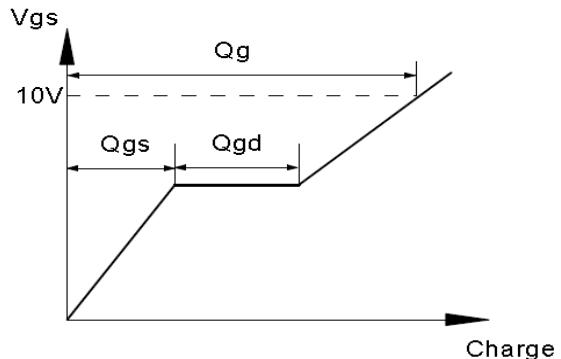
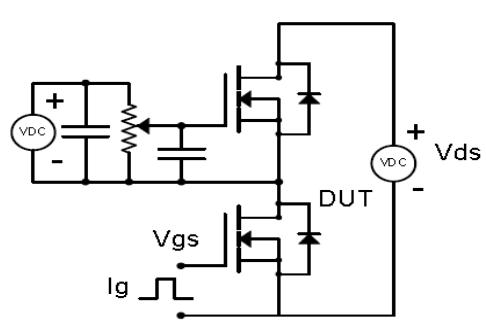


Fig 12: Max. Transient Thermal Impedance

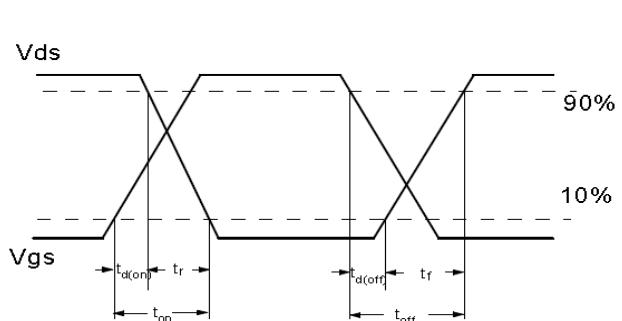
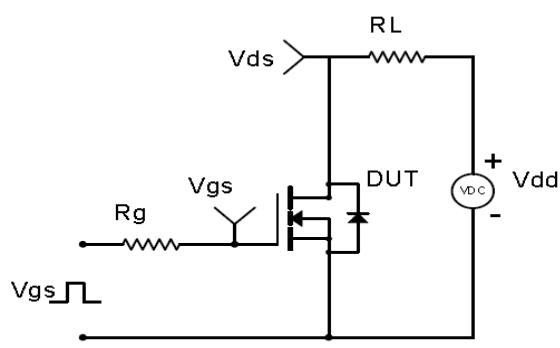


Test Circuit & Waveform

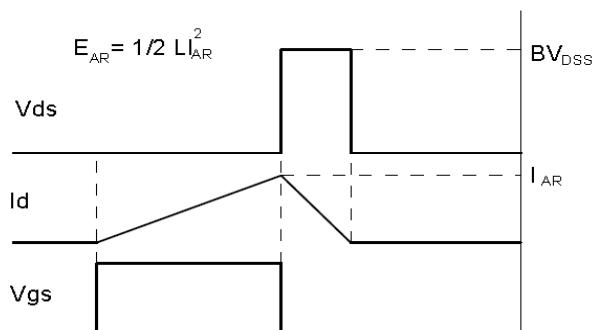
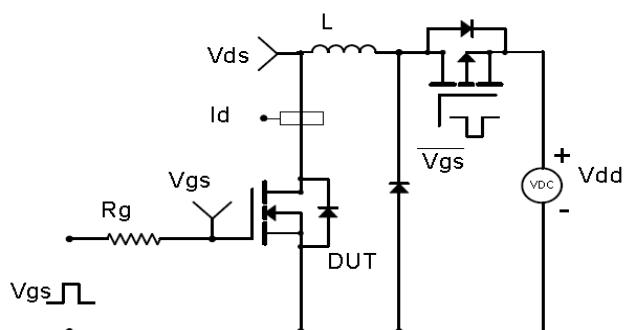
Gate Charge Test Circuit & Waveform



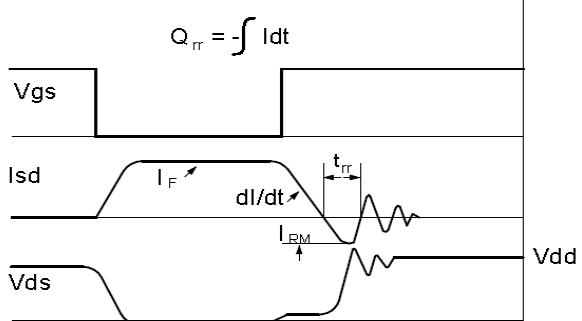
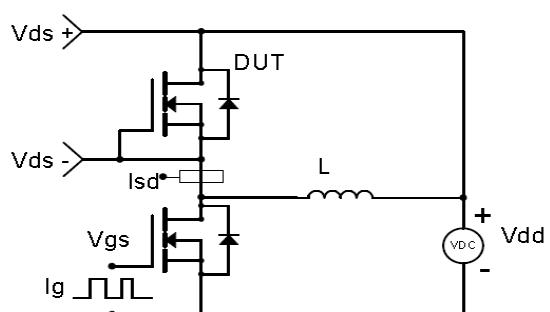
Resistive Switching Test Circuit & Waveforms

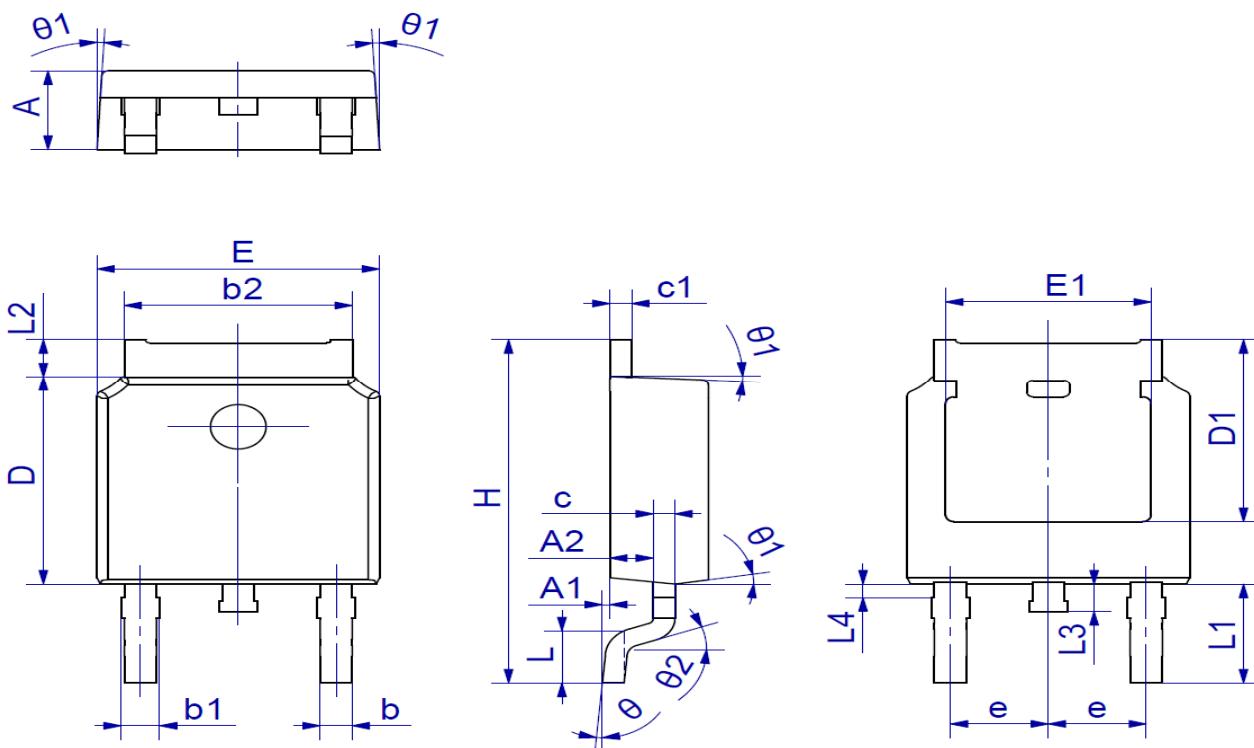


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Outline: TO-252-3L


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2	2.6	0.079	0.102
A1	0	0.15	0.000	0.006
A2	0.76	1.36	0.030	0.054
b	0.61	0.85	0.024	0.033
b1	0.71	0.91	0.028	0.036
b2	5.04	5.64	0.198	0.222
c	0.508 TYP.		0.02 TYP.	
c1	0.508 TYP.		0.02 TYP.	
D	5.7	6.3	0.224	0.248
D1	5	5.6	0.197	0.220
E	6.3	6.9	0.248	0.272
E1	4.55	5.15	0.179	0.203
e	2.286 TYP.		0.09 TYP.	
H	9.65	10.4	0.380	0.409
L	1.4	1.7	0.055	0.067
L1	2.90 REF.		0.114 REF.	
L2	0.75	1.35	0.030	0.053
L3	0.6	1.2	0.024	0.047
θ	0°	10°	0°	10°
θ1	5°	9°	5°	9°
θ2	25° REF.		25° REF.	



华润微电子(重庆)有限公司

CRTD063N04L

Trench N-MOSFET 40V, 4.5mΩ, 80A

Revision History

Revison	Date	Major changes
1.0	2018/4/24	Release of formal version

Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.

